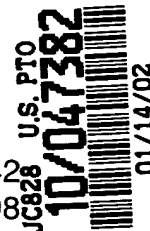


EV 026161597

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. 09/026,042
Priority Filing Date February 19, 1998
Inventor Sujit Sharan et al.
Assignee Micron Technology, Inc. and Applied Materials, Inc.
Priority Group Art Unit 1763
Priority Examiner P. Hassanzadeh Ph.D.
Attorney's Docket No. MI22-1902
Title: RF Powered Plasma Enhanced Chemical Vapor Deposition Reactor and Methods
of Effecting Plasma Enhanced Chemical Vapor Deposition



INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending application Serial No. 09/026,042, filed February 19, 1998, upon which the above-identified application relies for a priority date under 35 U.S.C. §120. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2). As a courtesy, Applicant submits copies of the cited foreign references and articles for review.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 324.14.2002

A handwritten signature in black ink, appearing to read "Frederick M. Fliegel".

Frederick M. Fliegel, Ph.D.
Reg. No. 36,138

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1902SERIAL NO.
Filed Concurrently HerewithLIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Sujit Sharan et al.

FILING DATE

GROUP

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